Martin Linck

List of Publications by Year in descending order

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#	Article	IF	CITATIONS
1	Electron Holography: Applications to Materials Questions. Annual Review of Materials Research, 2007, 37, 539-588.	9.3	116
2	Chromatic Aberration Correction for Atomic Resolution TEM Imaging from 20 to 80ÂkV. Physical Review Letters, 2016, 117, 076101.	7.8	99
3	Efficient diffractive phase optics for electrons. New Journal of Physics, 2014, 16, 093039.	2.9	67
4	State of the art in atomic resolution off-axis electron holography. Ultramicroscopy, 2012, 116, 13-23.	1.9	51
5	Origins and demonstrations of electrons with orbital angular momentum. Philosophical Transactions Series A, Mathematical, Physical, and Engineering Sciences, 2017, 375, 20150434.	3.4	39
6	Electron Holography with a <i>C</i> _{<i>s</i>} -Corrected Transmission Electron Microscope. Microscopy and Microanalysis, 2008, 14, 68-81.	0.4	33
7	Off-axis electron holography in an aberration-corrected transmission electron microscope. Philosophical Transactions Series A, Mathematical, Physical, and Engineering Sciences, 2009, 367, 3773-3793.	3.4	23
8	Ferroelectric effects in individual BaTiO <mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML" display="inline"><mml:msub><mml:mrow /><mml:mn>3</mml:mn></mml:mrow </mml:msub>nanocrystals investigated by electron holography. Physical Review B, 2012, 85, .</mml:math 	3.2	18
9	Aberration corrected STEM by means of diffraction gratings. Ultramicroscopy, 2017, 182, 36-43.	1.9	15
10	Automatic software correction of residual aberrations in reconstructed HRTEM exit waves of crystalline samples. Advanced Structural and Chemical Imaging, 2016, 2, 15.	4.0	14
11	Test and characterization of a new post-column imaging energy filter. Advances in Imaging and Electron Physics, 2019, 212, 35-70.	0.2	14
12	Aberration Correction and Electron Holography. Microscopy and Microanalysis, 2010, 16, 434-440.	0.4	12
13	A flexible multi-stimuli in situ (S)TEM: Concept, optical performance, and outlook. Ultramicroscopy, 2015, 151, 31-36.	1.9	9
14	Optimum aberration coefficients for recording high-resolution off-axis holograms in a Cs-corrected TEM. Ultramicroscopy, 2013, 124, 77-87.	1.9	7
15	Aberration-Corrected STEM by Means of Diffraction Gratings. Microscopy and Microanalysis, 2014, 20, 946-947.	0.4	7
16	Autocorrected off-axis holography of two-dimensional materials. Physical Review Research, 2020, 2, .	3.6	5
17	Exploiting the full potential of the advanced two-hexapole corrector for STEM exemplified at 60kV. Ultramicroscopy, 2022, 233, 113440.	1.9	5
18	On Proper Phase Contrast Imaging in Aberration Corrected TEM. Microscopy and Microanalysis, 2014, 20. 926-927.	0.4	2

#	Article	IF	CITATIONS
19	Off-axis electron holography: Materials analysis at atomic resolution. International Journal of Materials Research, 2022, 97, 890-898.	0.3	1
20	Electron Microscopy with Structured Electrons. Microscopy and Microanalysis, 2017, 23, 448-449.	0.4	0
21	Off-axis Electron Holography on 2D Materials with Small Coherent and Incoherent Aberrations. Microscopy and Microanalysis, 2021, 27, 128-129.	0.4	0